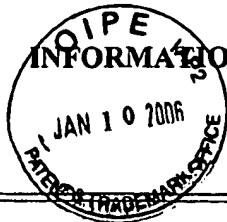


IDS 1/10/06

DPP:iar 01/04/06 1011-54375-01 469545 109-013

**INFORMATION DISCLOSURE STATEMENT  
BY APPLICANT**



Attorney Docket Number	1011-54375-01
Application Number	09/620,021
Filing Date	July 20, 2000
First Named Inventor	Rajski
Art Unit	2133
Examiner Name	Phung M. Chung

**U.S. PATENT DOCUMENTS**

Copies of U.S. Patent documents do not need to be provided, unless requested by the Patent and Trademark Office. For patents, provide the patent number and the issue date. For published U.S. applications, provide the publication number and the publication date. For unpublished pending patent applications, provide the application number and the filing date.

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EXAMINER  
SIGNATURE:

/Phung Chung/

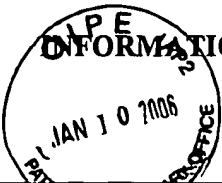
DATE  
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06/27/2006

\* Examiner: Initial if reference considered, whether or not in conformance with MPEP 609. Draw line through cite if not in conformance and not considered. Include copy of this form with next communication to applicant.

IDS 1/10/06

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EXAMINER SIGNATURE:	/Phung Chung/	DATE CONSIDERED:	06/27/2006
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IDS 12/22/05

DPP/PMB:iar 12/13/05 1011-54375-01 109-013

# INFORMATION DISCLOSURE STATEMENT BY APPLICANT



Attorney Docket Number	1011-54375-01
Application Number	09/620,021
Filing Date	July 20, 2000
First Named Inventor	Rajski
Art Unit	2133
Examiner Name	Phung M. Chung

## U.S. PATENT DOCUMENTS

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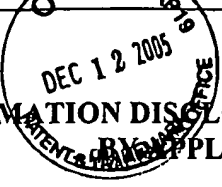
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 <b>INFORMATION DISCLOSURE STATEMENT</b> <b>BY APPLICANT</b>	Attorney Docket Number	1011-54375-01
	Application Number	09/620,021
	Filing Date	July 20, 2000
	First Named Inventor	Rajski
	Art Unit	2133
	Examiner Name	Phung M. Chung

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Examiner's Initials*	Cite No. (optional)	

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